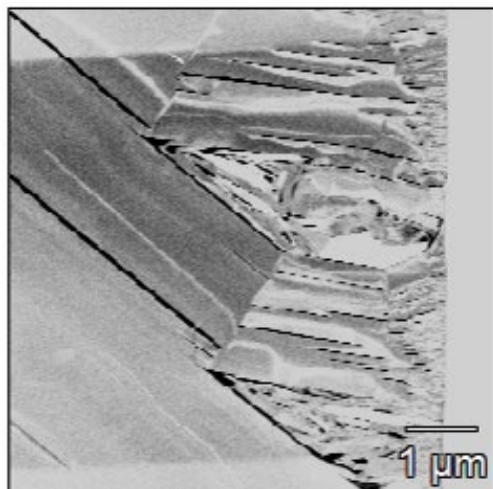
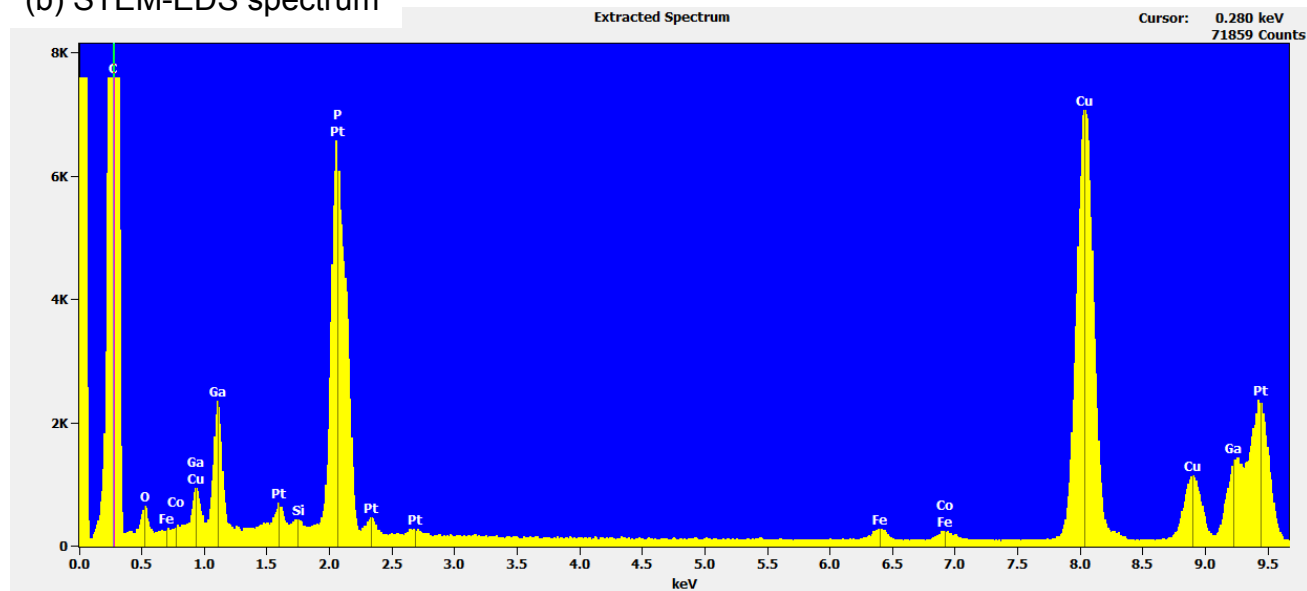


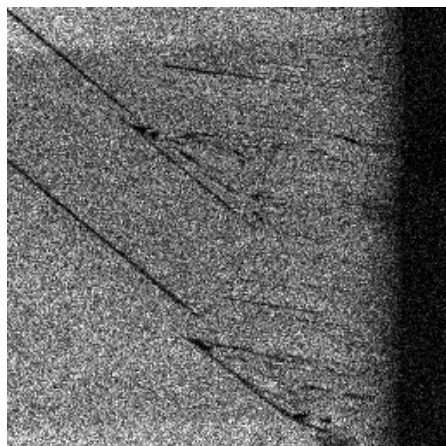
(a) STEM



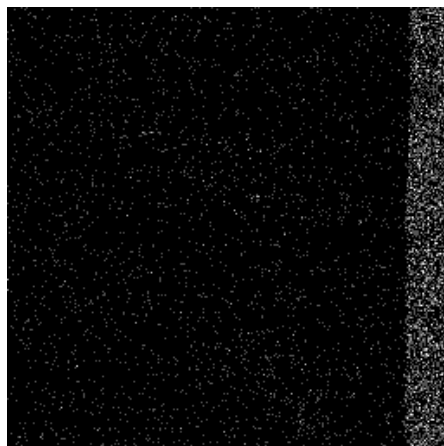
(b) STEM-EDS spectrum



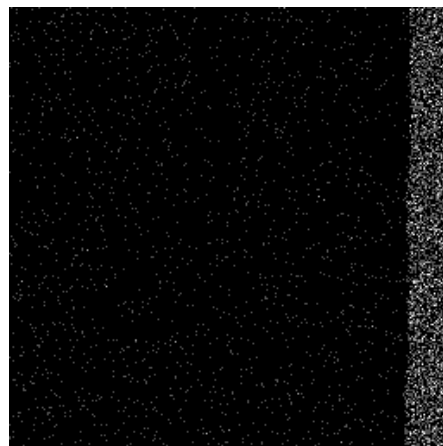
(c) C K



(d) Si K



(e) Al K



(f) O K

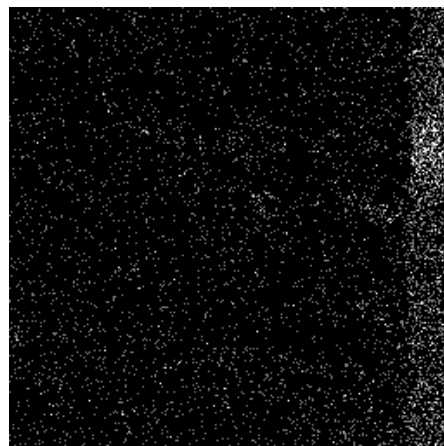


Figure S1 STEM-EDS mapping data. (a) STEM image of mapped area, (b) EDS spectrum of the entire mapped area. (c) to (f) shows element maps of carbon (C), silicon (Si), aluminum (Al), and oxygen (O), respectively. Only C was detected in the map area, and impurities such as Si, Al and O were not detected. In the EDS spectrum, Fe and Co peaks are derived from the TEM enclosure, Ga and Pt peaks were derived at the FIB process, and Cu peaks were derived from the sample holder.